New Trends in Deep Learning for Computer Vision

Guest Editors:

Prof. Dr. Cătălin Căleanu
Department of Communications, Politehnica University Timisoara, 300223 Timisoara, Romania

Prof. Dr. Chih-Hsien Hsia
Department of Computer Science and Information Engineering, National Ilan University, Yilan City 260, Taiwan

Deadline for manuscript submissions:
closed (15 July 2023)

Message from the Guest Editors

Deep neural networks (DNNs) and their associated learning paradigm deep learning (DL) currently represent key artificial intelligence (AI) paradigms. Multiple studies confirm that DNNs are offering the best solutions in many domains, including automotive, biometrics, robotics, cloud computing, medicine, manufacturing, and smart agriculture, to name just a few.

Humans are known to excel in computer vision (CV) tasks. Artificial NNs are loosely inspired by the human brain, having a hierarchical deep multi-layer structure, and are thus expected to provide relatively similar performances. Current research shows that among the most successful DL applications are those which utilize a wide range of neural architectures and learning algorithms in implementing CV operations, such as semantic segmentation, object detection, tracking, reconstruction, synthesis, prediction, perception, and classification.

Motivated by the fast dynamics of DL for the CV field, you are invited to contribute to a Special Issue of *Electronics* covering recent progress and achievements in utilizing deep learning for computer vision tasks.

Special Issue

Editor-in-Chief

Prof. Dr. Flavio Canavero
Department of Electronics and
Telecommunications,
Politecnico di Torino, 10129
Torino, Italy

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.
High Visibility: indexed within Scopus, SCIE (Web of Science), CAPlus / SciFinder, Inspec, Ei Compendex and other databases.
Journal Rank: JCR - Q2 (*Physics, Applied*) / CiteScore - Q2 (*Control and Systems Engineering*)

Contact Us